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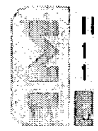
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1 **Dispute resolution for gTLD conflicts***de Vuyst, B.M.;*

System Sciences, 2002. HICSS. Proceedings of the 35th Annual Hawaii International Conference on , 7-10 Jan. 2002

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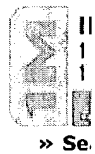
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